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Abstract Number: **235**  15th June 2024

Dear **Shamayeeta Dass**:

Thank you for submitting the abstract of your paper for WCEAM-2024 with the following title:

Title of the paper**: Deep Learning Based Image Processing For Detection Of Manufacturing Defects**

The decision of the technical committee on your abstract is: **ACCEPTED**

You can inform the other authors, if any, of the paper of this decision. You may now submit the full paper using the submission link (<https://equinocs.springernature.com/service/WCEAM2024>) within the due date as per the guidelines. In any correspondence please quote the above Abstract Number.

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